

**Search Notes**

Application/Control No.

10/775,384

Examiner

Raleigh Chiu

Applicant(s)/Patent under  
Reexamination

MEYER ET AL.

Art Unit

3711

**SEARCHED**

Class	Subclass	Date	Examiner
273	440, 459, 148R, 159, DIG. 26		
40	625, 632		
	633		
116	222, 225		
63	3		
	38-40	3/30/2006	RWC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR